

Substitute for Form 1449 A & B/PTO		<i>Complete if Known</i>	
<u>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</u>		Application Number	Not Yet Assigned
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		First Named Inventor	Markus MENGEL
		Art Unit	Not Yet Assigned
		Examiner Name	Not Yet Assigned
Sheet	1	of	1
		Attorney Docket Number	Q79656

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US 5 965 874		10/12/1999	THE FURUKAWA ELECTRIC CO., LTD
		US 5 396 329		3/7/1995	BRITISH AEROSPACE PLC
		US 5 298 972		3/29/1994	HEWLETT-PACKARD COMPANY
		US 5 227 623		7/13/1993	HEWLETT-PACKARD COMPANY
		US 5 166 752		11/24/1992	RUDOLPH RESEARCH CORPORATION
		US 6 204 924		3/20/2001	EXFO ELECTRO-OPTICAL ENGINEERING INC.
		US 6 312 373	B1	11/6/2001	NIKON CORPORATION
		US 6 344 898	B1	2/5/2002	NIKON CORPORATION
		US 2002/0024673	A1	2/28/2002	CHIDANE OUCHI

FOREIGN PATENT DOCUMENTS

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
		"OPTICAL SHOP TESTING", EDITED BY:DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
		MICHAEL I. SHRIBAK ET AL, "RETURN-PATH POLARIMETER FOR TWO DIMENSIONAL BIREFRINGENCE DISTRIBUTION MEASUREMENT", JULY 1999, SPIE, PAGES 144-145 AND 148-149, VOLUME 3654, DENVER COLORADO	
		S. BEREZHNA, ET AL, "ACCURACY OF WHOLE-FIELD MAPPING BY JONES MATRIX FOURIER PHOTOPOLARIMETER", 2000, PROCEEDINGS OF SPIE, PAGES 81-89, VOLUME 4148	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.